

Publikationen

(2011): Conductivity and Charge Trapping After Electrical Stress in Amorphous and Polycrystalline Al₂O₃-Based Devices Studied With AFM-Related Techniques. In: IEEE Transactions on Nanotechnology, vol. 10, no. 2, pp. 344-351.

(2009): Crystallization and silicon diffusion nanoscale effects on the electrical properties of Al₂O₃ based devices. In: Microelectronic Engineering, vol. 86, no. 7-9, pp. 1921-1924.